

EPERRY JOHNSON LABORATORY ACCREDITATION, INC.

Certificate of Accreditation

Perry Johnson Laboratory Accreditation, Inc. has assessed the Laboratory of:

A.V.C. Laboratory, Inc.

16542 NW 54th Avenue, Miami Gardens, FL 33014

(Hereinafter called the Organization) and hereby declares that Organization is accredited in accordance with the recognized International Standard:

ISO/IEC 17025:2017

This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (as outlined by the joint ISO-ILAC-IAF Communiqué dated April 2017):

Acoustic, Dimensional, Electrical, Mass, Force, and Weighing Devices, Optical. Mechanical, Time & Frequency and Thermodynamic Calibration (As detailed in the supplement)

Accreditation claims for such testing and/or calibration services shall only be made from addresses referenced within this certificate. This Accreditation is granted subject to the system rules governing the Accreditation referred to above, and the Organization hereby covenants with the Accreditation body's duty to observe and comply with the said rules.

For PJLA:

Tracy Szerszen President

Perry Johnson Laboratory Accreditation, Inc. (PJLA) 755 W. Big Beaver, Suite 1325 Troy, Michigan 48084

Initial Accreditation Date: August 11, 2016 Accreditation No.: 83028

Issue Date: December 16, 2022

Expiration Date: February 28, 2025

Certificate No.:

L22-858

The validity of this certificate is maintained through ongoing assessments based on a continuous accreditation cycle. The validity of this certificate should be confirmed through the PJLA website: www.pjlabs.com



A.V.C. Laboratory, Inc.

16542 NW 54th Avenue, Miami Gardens, FL, 33014 Contact Name: Freddy Vergel Phone: 786-542-8710

Accreditation is granted to the facility to perform the following calibrations:

| Acoustical | | | | | |
|----------------------|-------------------------|-----------------------|------------------------|--|--|
| MEASURED INSTRUMENT, | RANGE OR NOMINAL DEVICE | CALIBRATION AND | CALIBRATION | | |
| QUANTITY OR GAUGE | SIZE AS APPROPRIATE | MEASUREMENT | EQUIPMENT | | |
| | | CAPABILITY EXPRESSED | AND REFERENCE | | |
| | | AS AN UNCERTAINTY (±) | STANDARDS USED | | |
| Sound Level – | 94 dB | 0.32 dB | Sound Level Calibrator | | |
| Measure (Meters) FO | 114 dB | 0.32 dB | GIDEP | | |

Dimensional

| MEASURED INSTRUMENT, | RANGE OR NOMINAL DEVICE | CALIBRATION AND | CALIBRATION |
|-------------------------|---------------------------|------------------------------------|---------------------------|
| QUANTITY OR GAUGE | SIZE AS APPROPRIATE | MEASUREMENT CADADU ITV EVDESSED | EQUIPMENT |
| | | AS AN UNCERTAINTY (±) | STANDARDS USED |
| Calipers FO | 0.05 in to 24 in | (145 + 6L) uin | Gage Blocks, Long Blocks |
| 1 | (Resolution: 0.001 in) | | GIDEP & AVP-100 |
| | 0.05 in to 24 in | $(72 + 3L) \mu in$ | |
| | (Resolution: 0.000 5 in) | | |
| Micrometers FO | 0.05 in to 18 in | $(145 + 6L) \mu in$ | Gage Blocks, Long Blocks, |
| | (Resolution: 0.001 in) | | Optical Flat |
| | 0.05 in to 12 in | $(15 + 3L) \mu in$ | GIDEP & AVP-100 |
| | (Resolution: 0.000 1 in) | | |
| | 0.05 in to 4 in | (8 + 1.5L) μin | |
| | (Resolution: 0.000 05 in) | | |
| | 0.05 in to 4 in | $(2 + 0.5L) \mu in$ | |
| | (Resolution: 0.000 02in) | | |
| Height Gages FO | 0.001 in to 24 in | $(145 + 6L) \mu in$ | Gage Blocks, Long Blocks |
| | (Resolution: 0.001 in) | | GIDEP & AVP-100 |
| | 0.001 in to 24 in | $(72 + 3L) \mu in$ | |
| | (Resolution: 0.000 5 in) | | |
| | 0.001 in to 24 in | $(15 + 3L) \mu in$ | |
| | (Resolution: 0.000 1 in) | | |
| 2 | 0.001 in to 24 in | (8 + 1.5L) μin | |
| | (Resolution: 0.000 05 in) | | |
| Depth Gages FO | 0.001 in to 12 in | $(145 + 6L) \mu in$ | Gage Blocks, Long Blocks |
| | (Resolution: 0.001 in) | | GIDEP & AVP-100 |
| | 0.001 in to 12 in | $(72 + 3L) \mu in$ | |
| | (Resolution: 0.000 5 in) | | |
| | 0.001 in to 12 in | (8 + 1.5L) μin | |
| | (Resolution: 0.000 05 in) | | |
| Tool Maker | 0.001 in to 2 in | $(160 + 6L) \mu in$ | Master Glass Scales |
| Microscope – | | | GIDEP |
| Linearity ^{FO} | | | |



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| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
|---|--|---|---|
| Indicators FO | 0.001 in to 2 in | $(145 + 6L) \mu in$ | Gage Blocks |
| | (Resolution: 0.001 in) | | GIDEP & AVP-101 |
| | 0.001 in to 1 in | $(15 + 3L) \mu in$ | |
| | (Resolution: 0.000 1 in) | | |
| | 0.001 in to 2 in | $(32 + 3L) \mu in$ | |
| | (Resolution: 0.000 5 in) | | |
| | 0.001 in to 0.5 in | (8 + 1.5L) μin | |
| | (Resolution: 0.000 05 in) | | |
| | 0.000 01 in to 0.2 in | $(2 + 0.5L) \mu in$ | |
| | (Resolutions: 0.000 01 in) | · | |
| End Rods FO | Up to 1 in | (9 + 1.5L) μin | Starrett Multi-Axis |
| | 2 in to 4 in | $(15 + 3L) \mu in$ | w/Precision probe, Gage |
| | 5 in to 8 in | $(23 + 6L) \mu in$ | GIDEP & AVP-103 |
| | 9 in to 11 in | $(30 + 6L) \mu in$ | |
| | 12 in to 18 in | (38 + 6L) μin | |
| | 19 in to 24 in | $(45 + 6L) \mu in$ | |
| Surface Plate – | Up to 72 in diagonal | 65 μin | Repeat-o-meter, Starrett |
| Repeatability ^{FO} | | | Multi-Axis |
| | | | GIDEP |
| Surface Roughness | 2 μin to 500 μin | 1.0 µin | Roughness Specimen |
| Tester – Ra ^{FO} | | | GIDEP |
| Pin Gages ^{FO} | 0.001 in to 1.000 in | | Z-Mike Laser Micrometer |
| | (Class ZZ) | 65 μin | GIDEP & AVP-107 |
| | (Class Z) | 40 µin | |
| | (Class X) | 25 µin | |
| | (Class XX) | 20 µin | |
| Steel Ruler & Master | 0.001 in to 36 in | $(145 + 6L) \mu in$ | Gage Blocks, Long Blocks |
| Scales ^{FO} | (Resolution: 0.001 in) | | AVP-125 |
| | 0.001 in to 2 in | $(160 + 6L) \mu m$ | |
| | (Resolution: 0.000 l in) | | |
| | 0.001 in to 12 in | $(350 + 6L) \mu in$ | |
| | (Resolution: 0.000 7 in) | | |



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| Dimensional | | | |
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| Bore Measurement Devices FO | 0.125 in to 4 in | $(15 + 3L) \mu in$ | Gage Blocks Set Ring Gages Set |
| | (Resolution: 0.000 1 in) | | GIDEP |
| | 0.125 in to 4 in | $(72 + 3L) \mu in$ | |
| | (Resolution: 0.000 5 in) | | |
| Optical Comparator ^{FO} | | | Gage Blocks Set, Long Blocks, Angle Gage Blocks Set GIDEP |
| Linearity ^{FO} | 0.001 in to 12 in | $(350 + 6L) \mu in$ | & AVP-114 |
| Angular ^{FO} | 0.01 ° to 360 ° | 5 arc s | |
| Crimp Tools FO | 0.013 in to 0.073 in | 0.000 07 in | Go/No Go Pin Set |
| | | | GIDEP & AVP-100 |
| Almen Gages FO | 0.001 in to 0.5 in | $(15 + 3L) \mu in$ | Gage Blocks, GIDEP & AVP- |
| | (Resolutions: 0.000 1 in) | | 135 |
| | 0.001 in to 0.5 in | (8 + 1.5L) μin | |
| | (Resolutions: 0.000 05 in) | | |
| Test Indicators ^{FO} | up to 0.13 in (Resolutions: 0.000 01 in) | $(2 + 0.5L) \mu in$ | Gage Blocks GIDEP & AVP-101 |

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| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
|---|--|---|---|
| Equipment to Measure | 0.6 mV to 100 mV | $2.6\mu V/V + 3\mu V$ | Fluke 8846A |
| DC Voltage ^r | 100 mV to 1 V | $3.1 \mu V/V + 1.4 \mu V$ | GIDEP |
| | 1 V to 10 V | $1.6 \mu V/V + 13 \mu V$ | |
| | 10 V to 100 V | $12 \ \mu V/V + 1.9 \ mV$ | |
| | 100 V to 1 000 V | $11 \ \mu V/V + 2.4 \ mV$ | |
| Equipment to Output | 0.6 mV to 330 mV | $4 \mu V/V + 1 \mu V$ | Fluke 5520A |
| DC Voltage ^F | 330 mV to 3.3 V | $3 \mu V/V + 2 \mu V$ | GIDEP |
| | 3.3 V to 33 V | $3 \ \mu V/V + 20 \ \mu V$ | |
| | 33 V to 330 V | $3 \mu V/V + 150 \mu V$ | |
| | 330 V to 1 000 V | $3 \mu V/V + 1.5 mV$ | |



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| Electrical | | | |
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| Equipment to Output | 0.1 mA to 3.29 mA | $10 \ \mu A/A + 0.1 \ \mu A$ | Fluke 5520A |
| DC Current ^F | 3.3 mA to 32.9 mA | $10 \ \mu A/A + 0.2 \ \mu A$ | GIDEP |
| | 33 mA to 329.9 mA | $20 \ \mu A/A + 2.5 \ \mu A$ | |
| | 330 mA to 1.09 A | $20\ \mu A/A + 40\ \mu A$ | |
| | 1.1 A to 2.9 A | $65 \ \mu A/A + 40 \ \mu A$ | |
| | 3 A to 10.9 A | $60 \ \mu A/A + 500 \ \mu A$ | |
| | 11 A to 20.5 A | $90 \ \mu A/A + 750 \ \mu A$ | |
| Equipment to Measure | 0.1 mA to 1 mA | $0.04 \ \% + 0.2 \ \mu A$ | Fluke 8846A |
| DC Current ^F | 1 mA to 10 mA | $0.06 \% + 2.9 \mu A$ | GIDEP |
| | 10 mA to 100 mA | $0.04 \% + 20 \mu A$ | |
| | 100 mA to 400 mA | 0.05 % + 0.1 mA | |
| | 400 mA to 1 A | 0.07 % + 0.3 mA | |
| | 1 A to 3 A | 0.08 % + 1.2 mA | |
| | 3 A to 10 A | 0.15 % + 7.4 mA | |
| Equipment to Output | 0.1Ω to 10.9Ω | $10 \mu\Omega/\Omega + 5 m\Omega$ | Fluke 5520A |
| Resistance ^F | 11 Ω to 32.9 Ω | $6 \mu \Omega / \Omega + 5 m \Omega$ | GIDEP |
| | 33 Ω to 109.9 Ω | $5 \mu \Omega / \Omega + 5 m \Omega$ | |
| | 110 Ω to 329.9 Ω | $5 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 330 Ω to 1.09 k Ω | $5 \mu\Omega/\Omega + 5 m\Omega$ | |
| | 1.1 k Ω to 3.29 k Ω | $8 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | $3.3 \text{ k}\Omega$ to $10.9 \text{ k}\Omega$ | $8 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 11 kΩ to 32.9 kΩ | $8 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 33 kΩ to 109.9 kΩ | $8 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 110 kΩ to 329.9 kΩ | $8 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | $330 \text{ k}\Omega$ to $1.09 \text{ M}\Omega$ | $6 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 1.1 MΩ to 3.29 MΩ | $12 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 3.3 MΩ to 10.9 MΩ | $18 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 11 MΩ to 32.9 MΩ | $70 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 33 MΩ to 109.9 MΩ | $85 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | 110 MΩ to 329.9 MΩ | $280 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |
| | $330 \text{ M}\Omega$ to $1 \ 100 \text{ M}\Omega$ | $1 \ 100 \ \mu\Omega/\Omega + 5 \ m\Omega$ | |



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| Equipment to Measure | 0.1Ω to 10Ω | $60 \ \mu\Omega/\Omega + 2.3 \ m\Omega$ | Fluke 8846A |
| Resistance ^F | 10 Ω to 100 Ω | $30 \ \mu\Omega/\Omega + 6.9 \ m\Omega$ | GIDEP |
| | 100 Ω to 1 k Ω | $13 \ \mu\Omega/\Omega + 0.052 \ \Omega$ | |
| | 1 k Ω to 10 k Ω | $14 \ \mu\Omega/\Omega + 0.52 \ \Omega$ | |
| | 10 kΩ to 100 kΩ | $14 \ \mu\Omega/\Omega + 5.2 \ \Omega$ | |
| | 100 k Ω to 1 M Ω | $12 \ \mu\Omega/\Omega + 52 \ \Omega$ | |
| | $1 \text{ M}\Omega$ to $10 \text{ M}\Omega$ | $16 \ \mu\Omega/\Omega + 1.2 \ k\Omega$ | |
| | 10 M Ω to 100 M Ω | $43 \ \mu\Omega/\Omega + 47 \ k\Omega$ | |
| | 100 MΩ to 1 GΩ | $560 \ \mu\Omega/\Omega + 8.7 \ M\Omega$ | |
| Equipment to Output | 0.19 nF to 0.39 nF | 5 mF/F + 0.01 nF | Fluke 5520A |
| Capacitance ^F | 0.4 nF to 1.09 nF | 2 mF/F + 0.01 nF | GIDEP |
| | 1.1 nF to 3.29 nF | 1 mF/F + 0.01 nF | |
| | 3.3 nF to 10.9 nF | 1 mF/F + 0.01 nF | |
| | 11 nF to 32.9 nF | 1 mF/F + 0.1 nF | |
| | 33 nF to 109.9 nF | 1 mF/F + 0.1 nF | |
| | 110 nF to 329.9 nF | 1 mF/F + 0.3 nF | |
| | 0.33 μF to 1.09 μF | 1 mF/F + 1 nF | |
| | 1.1 μF to 3.29 μF | 1 mF/F + 3 nF | |
| | 3.3 µF to 10.9 µF | 1 mF/F + 10 nF | |
| | 11 μF to 32.9 μF | 1 mF/F + 30 nF | |
| | 33 μF to 109.9 μF | 1 mF/F + 100 nF | |
| | 110 µF to 329.9 µF | 1 mF/F + 300 nF | |
| | 0.33 µF to 1.09 mF | 1 mF/F + 1 μF | L Contraction of the second seco |
| | 1.1 mF to 3.29 mF | $1 \text{ mF/F} + 3 \mu \text{F}$ | |
| | 3.3 mF to 10.9 mF | $1 \text{ mF/F} + 10 \mu\text{F}$ | |
| | 11 mF to 32.9 mF | $1 \text{ mF/F} + 30 \mu\text{F}$ | |
| | 33 mF to 110 mF | $1 \text{ mF/F} + 100 \mu\text{F}$ | |



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Electrical MEASURED INSTRUMENT, RANGE OR NOMINAL CALIBRATION AND CALIBRATION QUANTITY OR GAUGE DEVICE SIZE AS MEASUREMENT EQUIPMENT APPROPRIATE CAPABILITY EXPRESSED AND REFERENCE STANDARDS USED AS AN UNCERTAINTY (±) 0.1 nF to 1 nF Equipment to Measure Flute 8846A $1.2\% + 26 \, \mathrm{pF}$ Capacitance ^F GIDEP 1 nF to 10 nF 0.3 % + 120 pF 10 nF to 100 nF 0.2% + 1.2 nF 0.2% + 12 nF 100 nF to 1 µF $1 \mu F$ to $10 \mu F$ 0.2 % + 120 nF10 µF to 100 µF $0.4 \% + 1.2 \mu F$ 100 µF to 1 mF $0.4 \% + 12 \mu F$ 1 mF to 10 mF $0.4 \% + 120 \mu F$ 10 mF to 100 mF 1.0% + 2.4 mF Equipment to Measure AC Voltage At the listed Frequencies F 3 Hz to 5 Hz 0.1 mV to 100 mV $35 \,\mu V/V + 0.05 \,mV$ 5 Hz to 10 Hz 0.1 mV to 100 mV $35 \,\mu V/V + 0.05 \,mV$ 10 Hz to 20 kHz 0.1 mV to 100 mV $4.5 \,\mu V/V + 0.05 \,mV$ 0.1 mV to 100 mV $5.8 \,\mu V/V + 0.09 \,mV$ 20 kHz to 50 kHz 50 kHz to 100 kHz 0.1 mV to 100 mV $10 \mu V/V + 0.4 mV$ $30 \,\mu V/V + 2.6 \,mV$ 100 kHz to 300 kHz 0.1 mV to 100 mV Equipment to Output AC Voltage Fluke 5520A At the listed Frequencies F GIDEP 10 Hz to 45 Hz 1 mV to 32.9 mV $100 \,\mu V/V + 6 \,\mu V$ 45 Hz to 10 kHz 1 mV to 32.9 mV $100 \,\mu V/V + 6 \,\mu V$ 10 kHz to 20 kHz 1 mV to 32.9 mV $100 \,\mu V/V + 6 \,\mu V$ 20 kHz to 50 kHz 1 mV to 32.9 mV $200 \,\mu V/V + 6 \,\mu V$ 50 kHz to 100 kHz $300 \,\mu V/V + 12 \,\mu V$ 1 mV to 32.9 mV 100 kHz to 500 kHz 1 mV to 32.9 mV $800 \ \mu V/V + 50 \ \mu V$ Equipment to Measure AC Voltage Fluke 8846A At the listed Frequencies F GIDEP 3 Hz to 5 Hz 100 mV to 1 V 0.29 % + 0.5 mV5 Hz to 10 Hz 100 mV to 1 V 0.29 % + 0.5 mV10 Hz to 20 kHz 100 mV to 1 V 0.03 % + 0.5 mV 20 kHz to 50 kHz 100 mV to 1 V $0.04 \ \% + 1.0 \ mV$ 50 kHz to 100 kHz 100 mV to 1 V 0.09 % + 4.0 mV100 kHz to 300 kHz 100 mV to 1 V 0.69 % + 2.6 mV



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| Equipment to Output AC Vo | Equipment to Output AC Voltage | | |
| At the listed Frequencies ^F | | | GIDEP |
| 10 Hz to 45 Hz | 33 mV to 329.9 mV | $30 \mu \text{V/V} + 8 \mu \text{V}$ | |
| 45 Hz to 10 kHz | 33 mV to 329.9 mV | $30 \ \mu V/V + 8 \ \mu V$ | |
| 10 kHz to 20 kHz | 33 mV to 329.9 mV | $30 \ \mu V/V + 8 \ \mu V$ | |
| 20 kHz to 50 kHz | 33 mV to 329.9 mV | $50\;\mu V/V + 8\;\mu V$ | |
| 50 kHz to 100 kHz | 33 mV to 329.9 mV | $80 \ \mu V/V + 32 \ \mu V$ | |
| 100 kHz to 500 kHz | 33 mV to 329.9 mV | $240~\mu V/V + 70~\mu V$ | |
| Equipment to Measure AC V At listed frequencies ^F | Voltage | | Fluke 8846A GIDEP |
| 3 Hz to 5 Hz | 1 V to 10 V | 0.01 % + 0.5 mV | |
| 5 Hz to 10 Hz | 1 V to 10 V | 0.01 % + 0.5 mV | |
| 10 Hz to 20 kHz | 1 V to 10 V | 0.004 % + 0.5 mV | |
| 20 kHz to 50 kHz | 1 V to 10 V | 0.009 % + 1.0 mV | |
| 50 kHz to 100 kHz | 1 V to 10 V | 0.03 % + 4.0 mV | |
| 100 kHz to 300 kHz | 1 V to 10 V | 0.04 % + 9.0 mV | |
| Equipment to Output AC Voltage At listed frequencies ^F | | | Fluke 5520A GIDEP |
| 10 Hz to 45 Hz | 0.33 V to 3.29 V | $30 \mu V/V + 50 \mu V$ | |
| 45 Hz to 10 kHz | 0.33 V to 3.29 V | $30 \mu V/V + 60 \mu V$ | |
| 10 kHz to 20 kHz | 0.33 V to 3.29 V | $30 \ \mu V/V + 60 \ \mu V$ | |
| 20 kHz to 50 kHz | 0.33 V to 3.29 V | $40 \ \mu V/V + 50 \ \mu V$ | |
| 50 kHz to 100 kHz | 0.33 V to 3.29 V | $60 \ \mu V/V + 125 \ \mu V$ | |
| 100 kHz to 500 kHz | 0.33 V to 3.29 V | $300 \ \mu V/V + 600 \ \mu V$ | N |
| Equipment to Measure AC Voltage At listed frequencies ^F | | | Fluke 8846A GIDEP |
| 3 Hz to 5 Hz | 10 V to 100 V | 0.11 % + 0.05 mV | |
| 5 Hz to 10 Hz | 10 V to 100 V | 0.11 % + 0.05 mV | |
| 10 Hz to 20 kHz | 10 V to 100 V | 0.03 % + 0.05 mV | |
| 20 kHz to 50 kHz | 10 V to 100 V | 0.1 % + 0.1 mV | |
| 50 kHz to 100 kHz | 10 V to 100 V | 0.3 % + 0.2 mV | |
| 100 kHz to 300 kHz | 10 V to 100 V | 2.5 % + 0.4 mV | |



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|--|---|---|---|--|
| Equipment to Output AC Voltage | | | Fluke 5520A | |
| At the listed Frequencies F | 2 2 V to 22 0 V | 20.0 V/V + 650.0 V | GIDEP | |
| 10 HZ 10 43 HZ | 5.5 V 10 52.9 V | $30 \mu v / v + 630 \mu v$ | _ | |
| 45 Hz to 10 kHz | 3.3 V to 32.9 V | $30 \mu \text{V}/\text{V} + 600 \mu \text{V}$ | _ | |
| 10 kHz to 20 kHz | 3.3 V to 32.9 V | $30 \mu \text{V}/\text{V} + 600 \mu \text{V}$ | _ | |
| 20 kHz to 50 kHz | 3.3 V to 32.9 V | $45 \mu V/V + 600 \mu V$ | _ | |
| 50 kHz to 100 kHz | 3.3 V to 32.9 V | $75 \mu V/V + 1 600 \mu V$ | | |
| Equipment to Output AC V At the listed Frequencies ^F | /oltage | | Fluke 5520A GIDEP | |
| 45 Hz to 1 kHz | 33 V to 329.9 V | $40 \ \mu V/V + 2 \ mV$ | | |
| 1 kHz to 10 kHz | 33 V to 329.9 V | $40 \mu V/V + 6 mV$ | - | |
| 10 kHz to 20 kHz | 33 V to 329.9 V | $40 \mu V/V + 6 mV$ | | |
| 20 kHz to 50 kHz | 33 V to 329.9 V | $100 \mu V/V + 6 mV$ | - | |
| 50 kHz to 100 kHz | 33 V to 329.9 V | $2\ 000\ \mu V/V + 50\ 000\ \mu V$ | - | |
| Equipment to Measure AC At the listed Frequencies ^F | Voltage | | Fluke 8846A GIDEP | |
| 3 Hz to 5 Hz | 100 V to 1 000 V | 0.11 % + 0.3 mV | | |
| 5 Hz to 10 Hz | 100 V to 1 000 V | 0.11 % + 0.3 mV | | |
| 10 Hz to 20 kHz | 100 V to 1 000 V | 0.07 % + 0.3 mV | | |
| 20 kHz to 50 kHz | 100 V to 1 000 V | 0.04 % + 0.3 mV | | |
| 50 kHz to 100 kHz | 100 V to 1 000 V | 0.4 % + 0.5 mV | | |
| 100 kHz to 300 kHz | 100 V to 1 000 V | 0.4 % + 0.5 mV | | |
| Equipment to Output AC V At the listed Frequencies ^F | Equipment to Output AC Voltage | | | |
| 45 Hz to 1 kHz | 330 V to 1 020 V | $35 \mu V/V + 10 mV$ | | |
| 1 kHz to 5 kHz | 330 V to 1 020 V | $35 \mu V/V + 10 mV$ | - | |
| 5 kHz to 10 kHz | 330 V to 1 020 V | $35 \mu V/V + 10 mV$ | | |
| Equipment to Measure AC At the listed Frequencies ^F | Current | | Fluke 8846A GIDEP | |
| 3 Hz to 5 Hz | 0.1 mA to 1 mA | $0.03 \ \% + 0.8 \ \mu A$ | 1 | |
| 5 Hz to 10 Hz | 0.1 mA to 1 mA | $0.03 \ \% + 0.8 \ \mu A$ | | |
| 10 Hz to 5 kHz | 0.1 mA to 1 mA | $0.008 \ \% + 0.8 \ \mu A$ | | |
| 5 kHz to 10 kHz | 0.1 mA to 1 mA | $0.02 \% + 2.6 \mu A$ | | |



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| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED | | |
|---|--|---|---|--|--|
| Equipment to Output AC Cu | urrent | | Fluke 5520A | | |
| At the listed Frequencies ¹ | 0.020 m to 0.320 m | $300 \pm 4/4 \pm 0.1 \pm 4$ | GIDEP | | |
| 10 HZ to 20 HZ | 0.029 IIIA to 0.329 IIIA | $300 \mu\text{A/A} + 0.1 \mu\text{A}$ | | | |
| 20 Hz to 45 Hz | 0.029 mA to 0.329 mA | $200 \mu A/A + 0.1 \mu A$ | - | | |
| 45 Hz to 1 kHz | 0.029 mA to 0.329 mA | $150 \mu\text{A/A} + 0.1 \mu\text{A}$ | - | | |
| I kHz to 5 kHz | 0.029 mA to 0.329 mA | $300 \mu\text{A/A} + 0.2 \mu\text{A}$ | - | | |
| 5 kHz to 10 kHz | 0.029 mA to 0.329 mA | 450 μA/A + 0.2 μA | | | |
| Equipment to Measure AC At the listed Frequencies ^F | Current | | Fluke 8846A GIDEP | | |
| 3 Hz to 5 Hz | 1 mA to 10 mA | 0.03 % + 8 µA | | | |
| 5 Hz to 10 Hz | 1 mA to 10 mA | 0.03 % + 8 µA | | | |
| 10 Hz to 5 kHz | 1 mA to 10 mA | 0.01 % + 8 µA | | | |
| 5 kHz to 10 kHz | 1 mA to 10 mA | 0.01 % + 26 µA | - | | |
| Equipment to Output AC Cu At the listed Frequencies ^F | Equipment to Output AC Current At the listed Frequencies ^F | | | | |
| 10 Hz to 20 Hz | 0.33 mA to 3.29 mA | $250 \mu A/A + 0.2 \mu A$ | 1 | | |
| 20 Hz to 45 Hz | 0.33 mA to 3.29 mA | 200 µA/A + 0.2 µA | | | |
| 45 Hz to 1 kHz | 0.33 mA to 3.29 mA | $150 \mu A/A + 0.2 \mu A$ | 5 | | |
| 1 kHz to 5 kHz | 0.33 mA to 3.29 mA | 150 μA/A + 0.2 μA | | | |
| 5 kHz to 10 kHz | 0.33 mA to 3.29 mA | $900 \ \mu A/A + 0.3 \ \mu A$ | | | |
| 10 kHz to 30 kHz | 0.33 mA to 3.29 mA | 900 µA/A + 0.6 µA | | | |
| Equipment to Measure AC At the listed Frequencies ^F | Current | | Fluke 8846A GIDEP | | |
| 3 Hz to 5 Hz | 10 mA to 100 mA | 0.03 % + 81 µA | | | |
| 5 Hz to 10 Hz | 10 mA to 100 mA | 0.03 % + 81 µA | | | |
| 10 Hz to 5 kHz | 10 mA to 100 mA | $0.01 \ \% + 81 \ \mu A$ | | | |
| 5 kHz to 10 kHz | 10 mA to 100 mA | 0.03 % + 0.26 mA | | | |
| Equipment to Output AC Co At the listed Frequencies ^F | Fluke 5520A GIDEP | | | | |
| 10 Hz to 20 Hz | 3.3 mA to 32.9 mA | $150 \ \mu A/A + 3 \ \mu A$ | | | |
| 20 Hz to 45 Hz | 3.3 mA to 32.9 mA | $150 \ \mu A/A + 2 \ \mu A$ | | | |
| 45 Hz to 1 kHz | 3.3 mA to 32.9 mA | $150 \ \mu A/A + 2 \ \mu A$ | | | |
| 1 kHz to 5 kHz | 3.3 mA to 32.9 mA | $150 \mu A/A + 2 \mu A$ | | | |
| 5 kHz to 10 kHz | 3.3 mA to 32.9 mA | $300 \mu A/A + 3 \mu A$ | | | |
| 10 kHz to 30 kHz | 3.3 mA to 32.9 mA | $900 \ \mu A/A + 4 \ \mu A$ | 1 | | |



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| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
| Equipment to Measure AC At the listed Frequencies ^F | Fluke 8846A GIDEP | | |
| 3 Hz to 5 Hz | 100 mA to 400 mA | 0.11 % of reading + 0.43 mA | |
| 5 Hz to 10 Hz | 100 mA to 400 mA | 0.11 % of reading + 0.43 mA | - |
| 10 Hz to 5 kHz | 100 mA to 400 mA | 0.11 % of reading + 2 mA | - |
| 5 kHz to 10 kHz | 100 mA to 400 mA | 0.30 % of reading + 2 mA | - |
| Equipment to Output AC Co At the listed Frequencies ^F | urrent | 1 | Fluke 5520A GIDEP |
| 10 Hz to 20 Hz | 33 mA to 329.9 mA | $150 \mu A/A + 20 \mu A$ | |
| 20 Hz to 45 Hz | 33 mA to 329.9 mA | $150 \mu A/A + 20 \mu A$ | |
| 45 Hz to 1 kHz | 33 mA to 329.9 mA | $150 \mu A/A + 20 \mu A$ | |
| 1 kHz to 5 kHz | 33 mA to 329.9 mA | $150 \mu A/A + 50 \mu A$ | |
| 5 kHz to 10 kHz | 33 mA to 329.9 mA | 300 μA/A + 100 μA | |
| 10 kHz to 30 kHz | 33 mA to 329.9 mA | 900 μA/A + 200 μA | |
| Equipment to Measure AC At the listed Frequencies ^F | Current | | Fluke 8846A GIDEP |
| 3 Hz to 5 Hz | 400 mA to 1 A | 0.03 % of reading + 0.8 mA | |
| 5 Hz to 10 Hz | 400 mA to 1 A | 0.03 % of reading + 0.8 mA | |
| 10 Hz to 5 kHz | 400 mA to 1 A | 0.02 % of reading + 0.8 mA | |
| 5 kHz to 10 kHz | 400 mA to 1 A | 0.03 % of reading + 6.1 mA | |
| Equipment to Output AC Current At the listed Frequencies ^F | | | Fluke 5520A GIDEP |
| 10 Hz to 45 Hz | 0.33 A to 1.09 A | $100 \mu A/A + 0.1 mA$ | |
| 45 Hz to 1 kHz | 0.33 A to 1.09 A | $100 \mu A/A + 0.1 mA$ | |
| 1 kHz to 5 kHz | 0.33 A to 1.09 A | 150 µA/A + 1.0 mA | |
| 5 kHz to 10 kHz | 0.33 A to 1.09 A | $400 \ \mu A/A + 5.0 \ mA$ | |
| Equipment to Measure AC At the listed Frequencies ^F | Current | | Fluke 8846A GIDEP |
| 3 Hz to 5 Hz | 1 A to 3 A | $300 \mu A/A + 0.1 mA$ | |
| 5 Hz to 10 Hz | 1 A to 3 A | $300 \mu A/A + 0.1 mA$ | |
| 10 Hz to 5 kHz | 1 A to 3 A | $400 \ \mu A/A + 1.0 \ mA$ | |
| 5 kHz to 10 kHz | 1 A to 3 A | $600 \mu A/A + 5.0 mA$ | |
| Equipment to Output AC Co At the listed Frequencies ^F | Fluke 5520A GIDEP | | |
| 10 Hz to 45 Hz | 1.1 A to 2.99 A | 1.8 mA/A + 100 µA | |
| 45 Hz to 1 kHz | 1.1 A to 2.99 A | $0.6 \text{ mA/A} + 100 \mu\text{A}$ | |
| 1 kHz to 5 kHz | 1.1 A to 2.99 A | 6 mA/A + 1 000 μA | |
| 5 kHz to 10 kHz | 1.1 A to 2.99 A | $25 \text{ mA/A} + 5 000 \mu\text{A}$ |] |
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| Electrical | | | |
|--|--|---|---|
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| Equipment to Measure AC | Current | | Fluke 8846A |
| At the listed Frequencies F | $2 \Lambda to 10 \Lambda$ | $0.05.0\%$ of reading ± 12.00 Å | GIDEP |
| 5 HZ to 5 HZ | | 0.05% of reading + 12 mA | |
| 5 Hz to 10 Hz | 3 A to 10 A | 0.05 % of reading + 12 mA | |
| 10 Hz to 5 kHz | 3 A to 10 A | 0.02 % of reading + 12 mA | |
| 5 kHz to 10 kHz | 3 A to 10 A | 0.02 % of reading + 12 mA | |
| Equipment to Output AC C At the listed Frequencies ^F | Current | | Fluke 5520A GIDEP |
| 45 Hz to 100 Hz | 3 A to 10.99 A | $300 \ \mu A/A + 2 \ mA$ | |
| 100 Hz to 1 kHz | 3 A to 10.99 A | $300 \ \mu A/A + 2 \ mA$ | |
| 1 kHz to 5kHz | 3 A to 10.99 A | $300 \ \mu A/A + 2 \ mA$ | |
| Equipment to Output AC O At the listed Frequencies ^F | Current | | |
| 45 Hz to 100 Hz | 11 A to 20.5 A | 250 μA/A + 5 mA | |
| 100 Hz to 1 kHz | 11 A to 20.5 A | $250 \mu A/A + 5 mA$ | |
| 1 kHz to 5 kHz | 11 A to 20.5 A | $300 \mu A/A + 5 mA$ | |
| Phase Angle – Generation | F | | Fluke 5520A |
| 10 Hz to 65 Hz | 0 ° to 360 ° | 0.05 ° | GIDEP |
| 65 Hz to 400 Hz | 0 ° to 360 ° | 0.05 ° | |
| 400 Hz to 5 kHz | 0 ° to 360 ° | 0.20 ° | - |
| Equipment to Output | 60 rpm to 600 rpm | 0.000 06 rpm | Fluke 5520A |
| rpm – Optical ^F | 600 rpm to 6 000 rpm | 0.000 5 rpm | LED fixture |
| | 6 000 rpm to 60 000 rpm | 0.007 rpm | GIDEP |
| | 60 000 rpm to 600 000 rpm | 0.072 rpm | |
| Equipment to Measure rpm – Optical / Contact ^F | 6 rpm to 99 999 rpm | 0.48 rpm + 0.004 % of Reading | Fluke 5345A Motor GIDEP |
| Oscilloscope | | | Fluke 5520A/SC1.1G |
| Level Sine Amp 50 kHz Ref. ^F | 5 mV to 5 $V_{(p-p)}$ | 0.3 mV + 3 % of Reading | GIDEP |
| Level Sine Flatness | 50 kHz to 100 MHz | 0.1 mV + 2 % of Reading | |
| 5 mV to 5.5 V Polative to 50 kHz | 100 MHz to 300 MHz | 0.1 mV + 2.5 % of Reading | |
| Reference ^F | 300 MHz to 600 MHz | 0.1 mV + 4.5 % of Reading | |
| | 600 MHz to 1 100 MHz | 0.1 mV + 5.5 % of Reading | |



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| Square Wave ^F 1 MΩ, 100 Hz | 1 mV to 150 $V_{(p-p)}$ | $40 \ \mu V + 0.2 \ \%$ of Reading | Fluke 5520A/SC1.1G GIDEP |
| Square Wave ^F 50 Ω, 1 kHz | $1 \text{ mV to } 6.6 \text{ V}_{(p-p)}$ | $40 \ \mu V + 0.35 \ \%$ of Reading | |
| Time Marker Output Into 50 Ω^{F} | 1 ns to 20 ms | 5 μs/s | |
| Rise Time ^F | \leq 300 ps | (0/ps / - 100) ps | |
| Temperature Calibration | -250 °C to -100 °C | 0.5 °C | Electrical Simulation of |
| Indication and Control | -100 °C to -25 °C | 0.16 °C | Thermocouple Output |
| Equipment used with Thermocouple Type E ^F | -25 °C to 350 °C | 0.14 °C | GIDEP |
| | 350 °C to 650 °C | 0.16 °C | GIDEA |
| | 650 °C to 1 000 °C | 0.21 °C | |
| Temperature Calibration | -210 °C to -100 °C | 0.27 °C | Fluke 5520A |
| Indication and Control | -100 °C to -30 °C | 0.16 °C | Electrical Simulation of |
| Thermocouple Type J F | -30 °C to 150 °C | 0.14 °C | GIDEP |
| | 150 °C to 760 °C | 0.17 °C | |
| | 760 °C to 1 200 °C | 0.23 °C | |
| Temperature Calibration | -200 °C to -100 °C | 0.33 °C | |
| Indication and Control | -100 °C to -25 °C | 0.18 °C | |
| Thermocouple Type K ^F | -25 °C to 120 °C | 0.16 °C | |
| | 120 °C to 1 000 °C | 0.26 °C | |
| | 1 000 °C to 1 372 °C | 0.40 ° C | |
| Temperature Calibration | -250 °C to -150 °C | 0.63 °C | |
| Indication and Control | -150 °C to 0 °C | 0.24 °C | |
| Thermocouple Type T ^F | 0 °C to 120 °C | 0.16 °C | |
| 1 71 | 120 °C to 400 °C | 0.14 °C | |
| Temperature Calibration | -200 °C to -80 °C | 0.04 °C | |
| Indication and Control | -80 °C to 0 °C | 0.04 °C | |
| RTD Pt 385 100 Ω F | 0 °C to 100 °C | 0.04 °C | |
| | 100 °C to 260 °C | 0.05 °C | |
| | 260 °C to 300 °C | 0.12 °C | |
| | 300 °C to 400 °C | 0.13 °C | |
| | 400 °C to 600 °C | 0.14 °C | |
| | 600 °C to 630 °C | 0.16 °C | |



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| Temperature Calibration | -200 °C to -80 °C | 0.05 °C | Fluke 5520A |
| Indication and Control | -80 °C to 0 °C | 0.05 °C | Electrical Simulation of |
| RTD Pt 3926 100 Ω F | 0 °C to 100 °C | 0.07 °C | GIDEP |
| | 100 °C to 300 °C | 0.09 °C | |
| | 300 °C to 400 °C | 0.1 °C | |
| | 400 °C to 630 °C | 0.12 °C | |
| Temperature Calibration | -200 °C to -190 °C | 0.25 °C | Fluke 5520A |
| Indication and Control | -190 °C to -80 °C | 0.04 °C | Electrical Simulation of |
| Pt 3916 100 Ω^{F} | -80 °C to 0 °C | 0.05 °C | GIDEP |
| | 0 °C to 100 °C | 0.06 °C | 012.21 |
| | 100 °C to 260 °C | 0.07 °C | |
| | 260 °C to 300 °C | 0.08 °C | |
| | 300 °C to 400 °C | 0.09 °C | |
| | 400 °C to 600 °C | 0.1 °C | |
| | 600 °C to 630 °C | 0.23 °C | |
| Temperature Calibration | -200 °C to -80 °C | 0.08 °C | |
| Indication and Control | -80 °C to 0 °C | 0.08 °C | |
| Pt 385 200 Q. ^F | 0 °C to 100 °C | 0.08 °C | |
| | 100 °C to 260 °C | 0.1 °C | |
| | 260 °C to 300 °C | 0.24 °C | |
| | 300 °C to 400 °C | 0.26 °C | |
| | 400 °C to 600 °C | 0.28 °C | |
| | 600 °C to 630 °C | 0.32 °C | |
| Temperature Calibration | -200 °C to -80 °C | 0.03 °C | |
| Indication and Control | -80 °C to 0 °C | 0.03 °C | |
| Pt 385 1 000 Ω F | 0 °C to 100 °C | 0.04 °C | |
| | 100 °C to 260 °C | 0.05 °C | |
| | 260 °C to 300 °C | 0.06 °C | |
| | 300 °C to 400 °C | 0.07 °C | |
| | 400 °C to 600 °C | 0.07 °C | |
| | 600 °C to 630 °C | 0.23 °C | |
| Temperature Calibration | -80 °C to 0 °C | 0.08 °C | |
| Indication and Control | 0 °C to 100 °C | 0.08 °C | |
| Ni 385 120 $\Omega^{\rm F}$ | 100 °C to 260 °C | 0.14 °C | |



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|---|---|---|--|
| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
| Temperature Calibration Indication and Control Equipment used with RTD Cu 427 120 Ω ^F | -100 °C to 260 °C | 0.3 °C | Fluke 5520A Electrical Simulation of RTD Output GIDEP |
| Temperature Measure | -200 °C | 0.05 °C | Fluke 8846A |
| RTD – Pt100 (DIN IEC 751, | -100 °C | 0.05 °C | GIDEP |
| type 385)* | 0 °C | 0.03 °C | |
| | 100 °C | 0.05 °C | |
| | 300 °C | 0.07 °C | |
| | 600 °C | 0.13 °C | |

Electrical

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| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
| DC Voltage – Measure ^{FO} | 1 kV to 40 kV | 0.011 V | Fluke 8846A & 80K40 GIDEP |
| | 1 A to 700 A | 0.01 % | Fluke 8846A & Shunt GIDEP |
| DC Current – Measuring Equipment ^F Clamp-On Only | 0.1 A to 1 000 A | 0.3 % of reading + 0.5 A | Fluke 5520A with coil GIDEP |
| Inductance Measuring Equipm Fixed Values | nent ^{FO} | | GenRad 1482 Series GIDEP |
| 1 mH | 100 Hz to 1 kHz | 1 μH | |
| 50 mH | 100 Hz to 1 kHz | 20 µH | |
| 100 mH | 100 Hz to 1 kHz | 40 µH | |
| Distortion – Measure ^{FO} (0 to 99.9) dB Fundamental Freq 20 Hz to 100 kHz | 50 Hz to 500 kHz | 0.1 % | HP 8903B GIDEP |
| Edge Rise Time – Measure ^F | < 300 ps | 24 ps | Tektronix TDS2012C GIDEP |



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| Signal Level Measuring Equip | oment ^F | | Output Level |
| (+23.98 to -56.02) dBm | 0.1 Hz to 20 MHz | 0.9 dB | HP 3325B, GIDEP |
| (+13.0 to -127.0) dBm | 100 kHz to 2000 MHz | 1.1 dBm | HP 8657B, GIDEP HP 8672A, GIDEP |
| (-10.0 to -90.0) dBm | 2 GHz to 18 GHz | 2.1 dBm | |
| Power Measurement – Amplitude ^F | -70dBm to +30 dBm | 1.1 dBm | HP 438A/ 8482A/ 8481D/ 8481A/ 11708A GIDEP |
| Power Meters – Readout | 3 μW | 0.25 % of reading + 6.2 nW | HP 11683A |
| Calibration | 10 μW | 0.25 % of reading + 6.2 nW | GIDEP |
| Zero Set | 3 μW | 0.25 % of reading + 6.2 nW | |
| Instrument Accuracy ^F | 30 μW | 0.25 % of reading + 6.2 nW | |
| | (100, 300) µW | 0.25 % of reading + 6.2 nW | |
| | (1, 2) mW | 0.25 % of reading + 6.2 nW | |
| | (10, 30, 100) mW | 0.25 % of reading + 6.2 nW | |
| Amplitude Modulation – Mea | sure ^F | | HP 8901B with 11722A |
| Rate: 50 Hz to 10 kHz, | 150 kHz to 10 MHz | 2 % of reading+1 digit | GIDEP |
| Depths: 5 % to 99 % | | | |
| Rate: 20 Hz to 10 kHz, | 150 kHz to 10 MHz | 3% of reading + 1 digit | |
| Depths: 5 % to 99% | | | |
| Rate: 20 Hz to 10 kHz, Depths: 5 % to 99% | 10 MHz to 1.3 GHz | 1 % of reading + 1 digit | |
| Rate: 20 Hz to 100 kHz, | 10 MHz to 1.3 GHz | 3% of reading + 1 digit | |
| Depths: 5 % to 99 % | | | |
| Frequency Modulation – Mea | sure ^F | | HP 8901B with 11722A |
| Rate: 20 Hz to 10 kHz, | 0.25 to 10 MHz | 4 % of reading + 1 digit | GIDEP |
| Dev.: \leq 40 kHz peak | | | |
| Rate: 50 Hz to 100 kHz, | 10 MHz to 1.3 GHz | 3 % of reading + 1 digit | |
| Dev.: $\leq 400 \text{ kHz peak}$ | | | |
| Rate: 20 Hz to 200 kHz, | 10 MHz to 1.3 GHz | 6 % of reading + 1 digit | |
| Dev.: $\leq 400 \text{ kHz peak}$ | | | |



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|---|---|--|--|
| Output Level ^F | -6 dBm to 120 dBm | AS AN UNCERTAINTY (±) | STANDARDS USED Collins VOR/ILS Signal Generator |
| Harmonics F | 0 dbin to 120 dbin | 0.007 0D | GIDEP |
| | | | - |
| >30.00 dB | 108 MHz to 118 MHz | 0.007 dB | |
| Marker Beacon | | | |
| >30.00 dB | 74 MHz to 76 MHz | 0.007 dB | - |
| Glideslope | 200 MIL- (+ 225 MIL- | 0.007.10 | |
| >25.00 dB Broadband Noise (SSB) ^F | 329 MHZ to 335 MHZ | 0.007 dB | - |
| > 115 dBc/Hz | 74 MHz to 76 MHz | 02dB | - |
| > 113 dBc/Hz | 108 MHz to 118 MHz | 0.2 dB | - |
| VOR Mode ^F | | 0.2 db | |
| Frequency | 30 Hz to 10 kHz | 230 uHz | |
| Distortion (Audio) ^F | | | |
| Preset < 0.25 % | 30 Hz Ref. | 0.005 % of reading | |
| < 0.50 % | 9960 Hz and 1020 Hz | 0.005 % of reading | |
| < 1.00 % | Aux Audio | 0.005 % of reading | |
| Variable < 1.000 % | 30 Hz | 0.005 % of reading | |
| < 1.500 % | 9960 Hz | 0.005 % of reading | |
| < 2.000 % | Aux Audio | 0.005 % of reading | - |
| Radial Range | Up to 360 ° | 0.01 % of reading | - |
| Amplitude Modulation ^F | - | | |
| Frequency | 1020 Hz | 23 µHz | |
| 30 Hz Var – Preset | 9960 Hz | 230 µHz | |
| Aux 30 Hz – 14 kHz | 30 Hz | 69 µHz | |
| | 14 kHz | 0.03 Hz | |
| Total Distortion ^F | 90 Hz | 33 µHz | - |
| | 150 Hz | 92 µHz | 1 |
| Preset < 1.00 % | 30 Hz | 0.005 % of reading | 1 |
| < 1.00 % | 1020 Hz | 0.005 % of reading | 1 |
| < 1.50 % | 9960 Hz | 0.005 % of reading | 1 |
| < 2.00 % | Aux 30 Hz to 14 kHz | 0.005 % of reading | 1 |
| Variable < 1.50 % | 30 Hz | 0.005 % of reading | 1 |
| < 2.00 % | 9960 Hz | 0.005 % of reading | 1 |
| < 3.00 % | Aux 30 Hz to 14 kHz | 0.005 % of reading | 1 |

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| EICUIICAI MEASUDED INSTRUMENT | DANCE OD NOMINAL | CALIERATION AND | CALIRDATION |
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| OUANTITY OR GAUGE | DEVICE SIZE AS | MEASUREMENT | EOUIPMENT |
| 2 000000000000000000000000000000000000 | APPROPRIATE | CAPABILITY EXPRESSED | AND REFERENCE |
| | | AS AN UNCERTAINTY (±) | STANDARDS USED |
| Localizer Mode | | | Collins VOR/ILS Signal Generator |
| Distortion (Audio) ^F | | | GIDEP |
| Preset < 0.25 % | 90 Hz to 150 Hz | 0.005 % of reading | |
| $< 0.50 \ \%$ | 1020 Hz | 0.005 % of reading | |
| < 1.00 % | Aux Audio | 0.005 % of reading | |
| Variable < 1.00 % | 90 Hz to 150 Hz | 0.005 % of reading | |
| < 1.50 % | Aux Audio | 0.005 % of reading | |
| Phase | 90 Hz to 150 Hz | 0.006 ° | |
| Amplitude Modulation ^F | | | 1 |
| Preset 20.00 % | 90 Hz to 150 Hz | 0.03 % of reading | |
| Variable 40.00 % | 90 Hz to 150 Hz | 0.06 % of reading | 1 |
| 1020 Hz (ident) | 90 Hz to 150 Hz | 0.05 % of reading | 1 |
| Aux Audio | 90 Hz to 150 Hz | 0.05 % of reading | 7 |
| Tone Distortion ^F | | | |
| Preset < 1.00 % | 90 Hz to 150 Hz | 0.001 % of reading |] |
| Variable < 1.50 % | 90 Hz to 150 Hz | 0.001 % of reading | |
| 1020 Hz (ident) < 1.00 % | 90 Hz to 150 Hz | 0.001 % of reading | |
| Aux Audio | 90 Hz to 150 Hz | 0.006 % of reading | |
| Glideslope Mode ^F | | | Collins VOR/ILS Signal Generator |
| Frequency | 30 Hz | 7 μHz | GIDEP |
| | 90 Hz | 21 µHz | |
| | 150 Hz | 35 µHz | |
| | 4 kHz | 0.001 Hz | |



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Accreditation is granted to the facility to perform the following calibrations:

| Electrical | | | |
|---|---|---|---|
| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
| Distortion (audio) ^F | · | • | Collins VOR/ILS Signal Generator |
| Preset < 0.25 % | 90 Hz to 150 Hz | 0.006 % | GIDEP |
| < 1.00 % | Aux Audio | 0.006 % | |
| Variable < 1.00 % | 90 Hz to 150 Hz | 0.006 % | |
| < 1.50 % | Aux Audio | 0.006 % | |
| Phase | 90 Hz to 150 Hz | 0.006 ° | |
| Amplitude Modulation ^F | · | | |
| Preset 40.00 % | 90 Hz to 150 Hz | 0.06 % | |
| Variable 80.00 % | 90 Hz to 150 Hz | 0.13 % | |
| Audio Aux ^F | | | |
| Preset 40.00 % | 90 Hz to 150 Hz | 0.06 % | |
| Variable 80.00 % | 90 Hz to 150 Hz | 0.13 % | |
| Tone Distortion ^F | | | |
| Preset < 1.20 % | 90 Hz to 150 Hz | 0.006 % | |
| Variable < 3.00 % | 90 Hz to 150 Hz | 0.006 % | |
| Aux Audio | 90 Hz to 150 Hz | 0.006 % | |
| Marker Beacon ^F | | | |
| Frequency Preset | 400 11- | 02 | |
| Outer Marker Middle Marker | 400 HZ | 92 µHz | |
| Inner Marker | 1 300 Hz | 33 µHz | |
| Amplitude Modulation ^F | 3 000 Hz | 690 µHz | |
| | 400 Hz | 92 µHz | |
| | 1 400 Hz | 33 µHz | |
| | 3 000 Hz | 690 µHz | |
| Aux Audio ^F | 400 Hz | 92 µHz | |
| | 1 400 Hz | 33 µHz | |
| | 3 000 Hz | 690 µHz | |
| Tone Distortion ^F | 90 Hz | 33 µHz | |
| | 150 Hz | 92 µHz | |
| VHF Comm ^F | 30 Hz | 69 µHz | |
| Frequency | 1 020 Hz | 24 µHz | |
| | 10 kHz | 0.002 Hz | |
| Amplitude Modulation ^F | 30 Hz | 69 µHz | |
| | 1 020 Hz | 24 µHz | |
| | 10 kHz | 0.002 Hz | |

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| Mass, Force, and Weight | ing Devices | | |
|--|---|---|---|
| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
| Tension/Compression Force ^F | 50 lbf to 500 lbf | 0.029 % of Reading | Morehouse Load Cell PC-500-TC GIDEP & AVP-112 |
| | 200 lbf to 2 000 lbf | 0.029 % of Reading | Morehouse Load Cell PC-2K-TC GIDEP & AVP-112 |
| | 1 000 lbf to 10 000 lbf | 0.029 % of Reading | Morehouse Load Cell PC-10K-TC GIDEP & AVP-112 |
| | 5 000 lbf to 50 000 lbf | 0.029 % of Reading | Morehouse Load Cell PC-50K-TC GIDEP & AVP-112 |
| Analytical Balances ^F | 1 mg to 120 g | 0.06 mg | Stainless Steel Weight Set ASTM 0, |
| Precision Balances ^F | $ \begin{array}{c} 1 mg to 620 g \\ (d = 1 mg) \\ 1 g to 8 000 g \\ (d = 1 g) \end{array} $ | 0.6 mg 1.2 mg | Stainless Steel Weight ASTM 1 GIDEP, NIST HB44-2018 & AVP- 105 |
| Bench Scale/ Balances FO | 25 kg to 125 kg (d = 1 g) | 0.21 g | NIST Class F Weights, GIDEP, NIST HB44-2018 & AVP-105 |
| Volume Delivery Instruments (Pipettes) ^F | 100 μL to 1 000 μL 1 mL to 10 mL 10 mL to 100 mL | 0.12 % of Reading0.025 % of Reading0.023 % of Reading | Stainless Steel Weight Set ASTM 0 Analytical Scale d = 0.1 mg Capacity: 120 g Vaisala HM170 & HMP77 |
| Compression Force ^{FO} | 30 000 lbf to 300 000 lbf | 0.17 % of Reading | Honeywell Load Cell CG-94-300K GIDEP & AVP-112 |
| Air Flow ^{FO} | 10 SCCM to 100 SCCM 100 SLPM to 1 000 SLPM | 0.82 % of Reading0.82 % of Reading | Alicat Scientific M-100SCCM, Alicat Scientific M1000SLPM Sierra Instruments 780S GIDEP & |
| Liquid Flow ^{FO} | 0.1 GPM to 300 GPM | 0.63 % of Reading | Flow Computers & Flow Turbines Set GIDEP & AVP-110 |



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Accreditation is granted to the facility to perform the following calibrations:

| Mechanical | | | |
|---|---|---|---|
| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCEPTAINTY (+) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
| Pressure Gauge and Transducer | 1.5 psi to 5 psi | 0.17 % of full scale | M101-GN0005 |
| FO | | | GIDEP & AVP-102 |
| | -15 psi to 30 psi | 0.047 % of full scale | DPI104-2-30PSI |
| | | | GIDEP & AVP-102 |
| | 25 psi to 100 psi | 0.072 % of full scale | DPI104-2-100PSI |
| | | | GIDEP & AVP-102 |
| | 75 psi to 300 psi | 0.052 % of full scale | DPI104-2-300PSI CIDED & AVD 102 |
| | 250 psi to 1 000 psi | 0.072 % of full scale | DPI104 2 1000PSI |
| | 250 psi to 1 000 psi | 0.072 /0 01 1ull scale | GIDEP & AVP-102 |
| | 1 250 psi to 5 000 psi | 0.089 % of full scale | DPI104-2-5000PSI |
| | | | GIDEP & AVP-102 |
| | 2 000 psi to 10 000 psi | 0.079 % of full scale | DPI104-2-10000PSI |
| | | | GIDEP & AVP-102 |
| | 4 000 psi to 20 000 psi | 0.04 % of full scale | DPI104-2-20000PSI |
| FO | | | GIDEP |
| Torque Wrench ^{FO} | 20 lbf·in to 200 lbf·in | 0.39 % Reading | TSD6000 / TSD011 |
| | 20 11 6 6 4 200 11 6 6 | | GIDEP & AVP-104 |
| | 30 lbf+ft to 300 lbf+ft | | 1SD6000 / 1SD321 |
| | 80 lbf. ft to 800 lbf. ft | | TDS821 / TDS1250 |
| | 00 101 11 10 000 101 11 | | GIDEP & AVP-104 |
| Indirect Verification of | 55 HRB | 0.28 HRB | Indirect verification per ASTM E18 |
| Rockwell Hardness Testers FO | 80 HRB | 0.61 HRB | |
| | 95 HRB | 0.60 HRB | |
| | 25 HRC | 0.57 HRC | |
| | 55 HRC | 0.54 HRC | |
| | 63 HRC | 0.53 HRC | |
| Air Data Test Set, Pitot Testers | -30 in Hg to 30 in Hg | 0.000 3 in Hg | Druck PACE6000 Aeronautical |
| F | | | Option & Control Module Aero w/ |
| | | | Barometric Reference Sensor |
| | | | GIDEP & AVP-116 |
| Equipment to Output Vibration | | | Modal Shop 9100D |
| 7 Hz to 10 Hz | 2 m/s^2 to 10 m/s^2 | 4.2 % of reading | GIDEF |
| 10 Hz to 30 Hz | 2 m/s^2 to 10 m/s ² | 3.2 % of reading | |
| 30 Hz to 2 kHz | 2 m/s^2 to 10 m/s ² | 1.9% of reading | |
| 2 kHz to 10 kHz | 2 m/s^2 to 10 m/s ² | 4.2 % of reading | |
| Air Flow Meters ^{FO} | 10 SI PM to 1 000 | 0.82% of Reading | Alicat Scientific M 100SI PM |
| | SLPM | 0.02 /0 Of Keauning | Alicat Scientific M1000SLPM |
| | | | Sierra Instruments 780S GIDEP & |
| | | | VP-110 |

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Accreditation is granted to the facility to perform the following calibrations:

| Thermodynamic | | | |
|--|---|---|--|
| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
| Flow Meter Equipment to Measure Air Velocity ^F | 4 m/s to 24 m/s | 1.0 % of reading | Hot wire Anemometer GIDEP |
| Equipment to Measure Temperature – Non-Contact Thermometer ^{FO} | -70 °C to 180 °C | 0.08 °C | Vaisala HMI70/HMP77, GIDEP & AVP-108 |
| Equipment to Measure Temperature – Contact Thermometer ^{FO} | -100 °C to 450 °C | 0.05 °C | Ultra Precise RTD Sensor, Fluke 8846A, GIDEP & AVP-108 |
| Thermometer Calibration ^{FO} | -25 °C to 140 °C | 0.50 % of reading | Fluke 9103 Dry-Well Calibrator, Ultra Precise RTD Sensor GIDEP & AVP-108 |
| Oven/Fridge Temperature Mapping ^{FO} | -25 °C to 120 °C 120 °C to 250 °C | 0.16 °C 0.26 °C | Fluke 2645A AMS2750 & AVP-108 |
| Equipment to Measure Humidity ^{FO} | 5 % RH to 100 % RH | 0.6 % RH | Vaisala HMI70/HMP77, GIDEP & AVP-108 |
| IR Thermometer & Thermal Video Devices ^{FO} | 50 °C to 500 °C | 0.5 % of reading | Infrared / Blackbody Calibrator GIDEP & AVP-108 |

Time & Frequency MEASURED INSTRUMENT. RANGE OR NOMINAL CALIBRATION AND CALIBRATION QUANTITY OR GAUGE DEVICE SIZE AS MEASUREMENT EQUIPMENT APPROPRIATE CAPABILITY EXPRESSED AND REFERENCE AS AN UNCERTAINTY (±) STANDARDS USED Stopwatch/Timer FO Direct comparison 0.000 6 % of calibration HP 5345A-counter method 1 h to 24 h time NIST SP 960-12.2009 ed & AVP-129 Totalize method 0.000 04 % of 1 h to 24 h calibration time

Optical

| MEASURED INSTRUMENT, QUANTITY OR GAUGE | RANGE OR NOMINAL DEVICE SIZE AS APPROPRIATE | CALIBRATION AND MEASUREMENT CAPABILITY EXPRESSED AS AN UNCERTAINTY (±) | CALIBRATION EQUIPMENT AND REFERENCE STANDARDS USED |
|---|---|---|---|
| Light (Light Meters) – Measure ^F | | | |
| UV | $1 \mu W/cm^2$ to 100 mW/cm ² | 3 % of reading | Radiometer and sensors ASTM E2297 |
| Visible | Up to 500 fc | 3 % of reading | |



A.V.C. Laboratory, Inc. 16542 NW 54th Avenue, Miami Gardens, FL, 33014 Contact Name: Freddy Vergel Phone: 786-542-8710

- 1. The CMC (Calibration and Measurement Capability) stated for calibrations included on this scope of accreditation represents the smallest measurement uncertainty attainable by the laboratory when performing a more or less routine calibration of a nearly ideal device under nearly ideal conditions. It is typically expressed at a confidence level of 95 % using a coverage factor k (usually equal to 2). The actual measurement uncertainty associated with a specific calibration performed by the laboratory will typically be larger than the CMC for the same calibration since capability and performance of the device being calibrated and the conditions related to the calibration may reasonably be expected to deviate from ideal to some degree.
- 2. The laboratories range of calibration capability for all disciplines for which they are accredited is the interval from the smallest calibrated standard to the largest calibrated standard used in performing the calibration. The low end of this range must be an attainable value for which the laboratory has or has access to the standard referenced. Verification of an indicated value of zero in the absence of a standard is common practice in the procedure for many calibrations but by its definition it does not constitute calibration of zero capacity.
- 3. The presence of a superscript F means that the laboratory performs calibration of the indicated parameter at its fixed location. Example: Outside Micrometer ^F would mean that the laboratory performs this calibration at its fixed location.
- 4. The presence of a superscript FO means that the laboratory performs calibration of the indicated parameter both at its fixed location and onsite at customer locations. Example: Outside Micrometer ^{FO} would mean that the laboratory performs this calibration at its fixed location and onsite at customer locations.
- 5. Measurement uncertainties obtained for calibrations performed at customer sites can be expected to be larger than the measurement uncertainties obtained at the laboratories fixed location for similar calibrations. This is due to the effects of transportation of the standards and equipment and upon environmental conditions at the customer site which are typically not controlled as closely as at the laboratories fixed location.
- 6. The term L represents length in inches or millimeters as appropriate to the uncertainty statement.